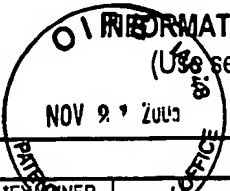
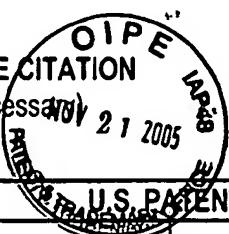


<div style="display: flex; justify-content: space-around; align-items: center;"> <div style="text-align: center;">  </div> <div style="text-align: center;">  </div> </div>				ATTY DOCKET NO. 1TL1026US (P16713)		SERIAL NO. 10/688,521	
				APPLICANT(S): Robert P. Meagley et al.			
				GROUP ART UNIT: 1752			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JMN	A.	6,162,592	12/19/2000	Taylor et al.			
	B.						
	C.						
	D.						
	E.						
U.S. PATENT APPLICATION PUBLICATIONS							
	F.						
	G.						
	H.						
	I.						
	J.						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	K.						
	L.						
	M.						
	N.						
	O.						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
JMN	P.	Lin et al., <i>Line Edge Roughness in Positive-Tone Chemically Amplified Resists: Effect of Additives and Processing Conditions</i> , Proceedings of the SPIE - The International Society for Optical Engineering, Vol. 4345, No. 1, Feb. 2001, pgs. 78-86.					
	Q.						
	R.						
	S.						
	T.						
	U.						
EXAMINER Andrew C. Wavre				DATE CONSIDERED January 18, 2006			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.